

<b>Notice of References Cited</b>	Application/Control No. 10/669,638	Applicant(s)/Patent Under Reexamination SEINO ET AL.	
	Examiner Rene Garcia, Jr.	Art Unit 2853	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,270,210	08-2001	Yamaguchi et al.	347/86
	B	US-6,536,861	03-2003	Usui et al.	347/7
	C	US-2003/0015036	01-2003	Young et al.	73/579
	D	US-2001/0040613	11-2001	Nakazawa et al.	347/86
	E	US-6,745,626	06-2004	Usui et al.	73/290R
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11258026 A	09-1999	Japan	OMATOI, NAOYUKI	G01F 23/296
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.